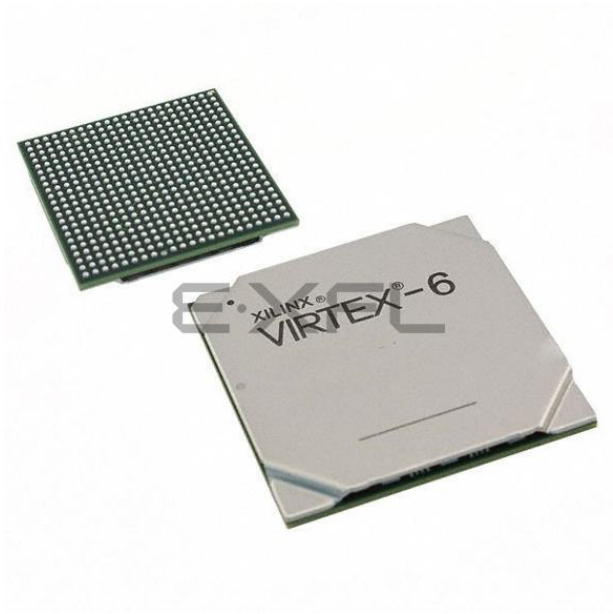
AMD Xilinx - XC6VCX195T-1FFG784I Datasheet



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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	15600
Number of Logic Elements/Cells	199680
Total RAM Bits	12681216
Number of I/O	400
Number of Gates	-
Voltage - Supply	0.95V ~ 1.05V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	784-BBGA, FCBGA
Supplier Device Package	784-FCBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6vcx195t-1ffg784i

Virtex-6 CXT FPGA Documentation

In addition to the data sheet information found herein, complete and up-to-date documentation of the Virtex-6 family of FPGAs is available on the Xilinx website and available for download:

Virtex-6 FPGA Configuration Guide **(UG360)**

This all-encompassing configuration guide includes chapters on configuration interfaces (serial and parallel), multi-bitstream management, bitstream encryption, boundary-scan and JTAG configuration, and reconfiguration techniques.

Virtex-6 FPGA SelectIO Resources User Guide **(UG361)**

This guide describes the SelectIO™ resources available in all the Virtex-6 CXT devices.

Virtex-6 FPGA Clocking Resources User Guide **(UG362)**

This guide describes the clocking resources available in all the Virtex-6 CXT devices, including the MMCM and clock buffers.

Virtex-6 FPGA Memory Resources User Guide **(UG363)**

This guide describes the Virtex-6 CXT device block RAM and FIFO capabilities.

Virtex-6 FPGA CLB User Guide **(UG364)**

This guide describes the capabilities of the configurable logic blocks (CLB) available in all Virtex-6 CXT devices.

Virtex-6 FPGA DSP48E1 Slice User Guide **(UG369)**

This guide describes the architecture of the DSP48E1 slice in Virtex-6 CXT FPGAs and provides configuration examples.

Virtex-6 FPGA GTX Transceivers User Guide **(UG366)**

This guide describes the GTX transceivers available in all the Virtex-6 CXT FPGAs.

Virtex-6 FPGA Tri-Mode Ethernet MAC User Guide **(UG368)**

This guide describes the dedicated tri-mode Ethernet media access controller (TEMAC) available in all the Virtex-6 CXT FPGAs.

Virtex-6 FPGA Data Sheet: DC and Switching Characteristics **(DS152)**

Reference this data sheet when considering device migration to the Virtex-6 LXT and SXT families. It contains the DC and Switching Characteristic specifications specifically for the Virtex-6 LXT and SXT families.

Virtex-6 FPGA Packaging and Pinout Specifications **(UG365)**

These specifications includes the tables for device/package combinations and maximum I/Os, pin definitions, pinout tables, pinout diagrams, mechanical drawings, and thermal specifications of the Virtex-6 LXT and SXT families. Reference these specifications when considering device migration to the Virtex-6 LXT and SXT families.

Configuration Bitstream Overview for CXT Devices

This section contains two tables similar to those in the *Virtex-6 FPGA Configuration Guide* only updated for the CXT family. The Virtex-6 CXT FPGA bitstream contains commands to the FPGA configuration logic as well as configuration data. Table 3 gives a typical bitstream length and Table 4 gives the specific device ID codes for the Virtex-6 CXT devices.

Table 3: **Virtex-6 CXT FPGA Bitstream Length**

Device	Total Number of Configuration Bits
XC6VCX75T	26,239,328
XC6VCX130T	43,719,776
XC6VCX195T	61,552,736
XC6VCX240T	73,859,552

Table 4: **Virtex-6 CXT FPGA Device ID Codes**

Device	ID Code (Hex)
XC6VCX75T	0x042C4093
XC6VCX130T	0x042CA093
XC6VCX195T	0x042CC093
XC6VCX240T	0x042D0093

FF484 Package Placement Diagrams

Figure 2 and Figure 3 show the placement diagrams for the GTX transceivers in the FF484 package.

Note: Unbonded locations in the FF484 package are:

- CX75T: X0Y8, X0Y9, X0Y10, X0Y11
- CX130T: X0Y0, X0Y1, X0Y2, X0Y3, and X0Y12, X0Y13, X0Y14, X0Y15

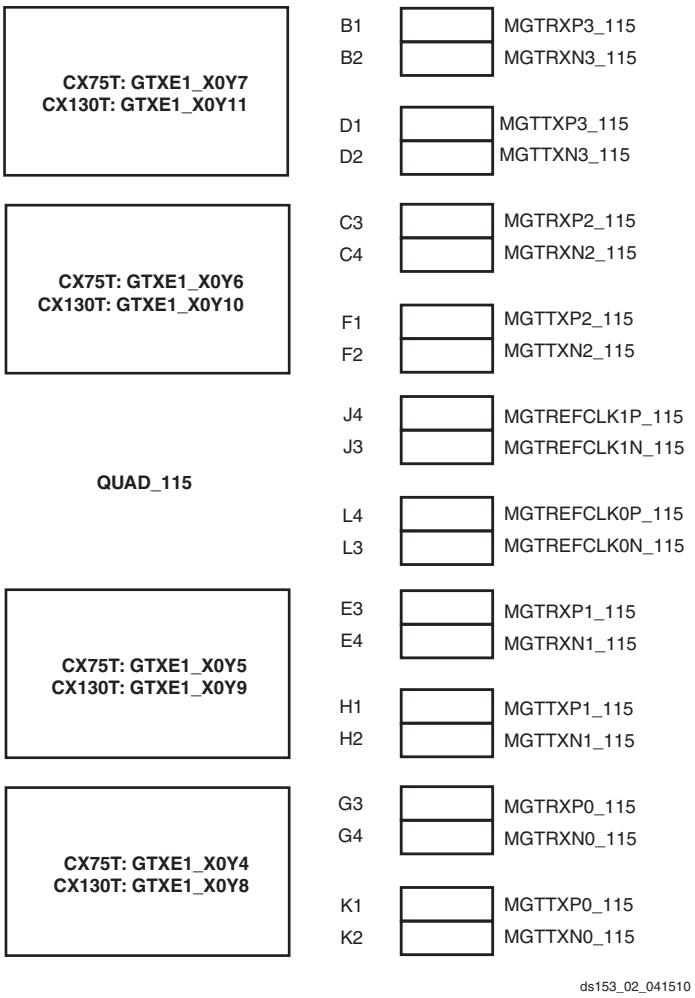

Figure 2: **Placement Diagram for the FF484 Package (1 of 2)**

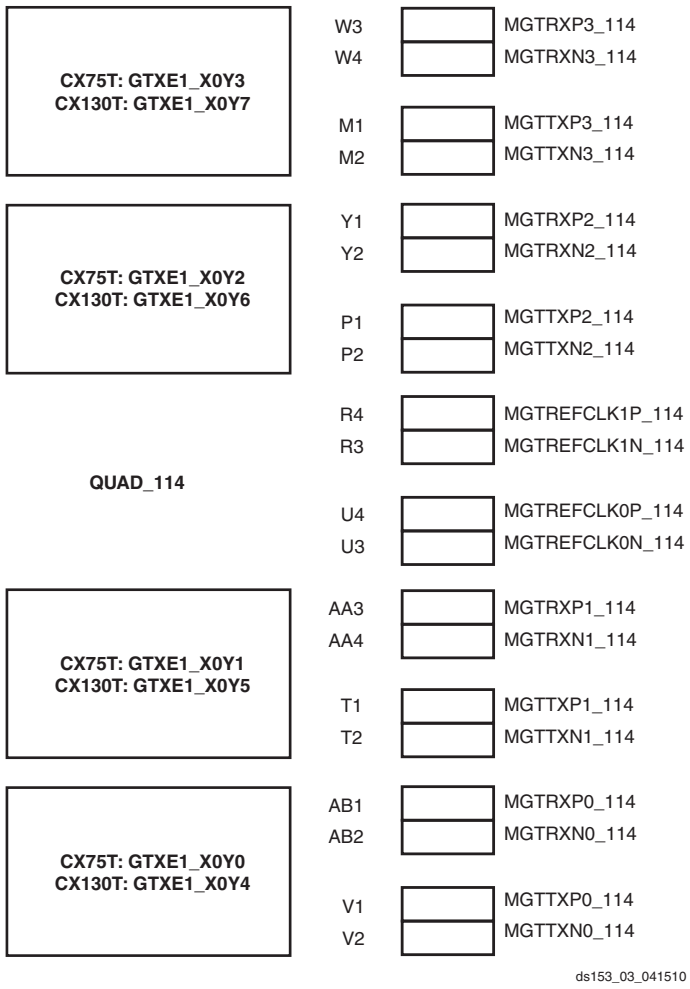

Figure 3: **Placement Diagram for the FF484 Package (2 of 2)**

FF1156 Package Placement Diagrams

Figure 7 through Figure 10 show the placement diagrams for the GTX transceivers in the FF1156 package.

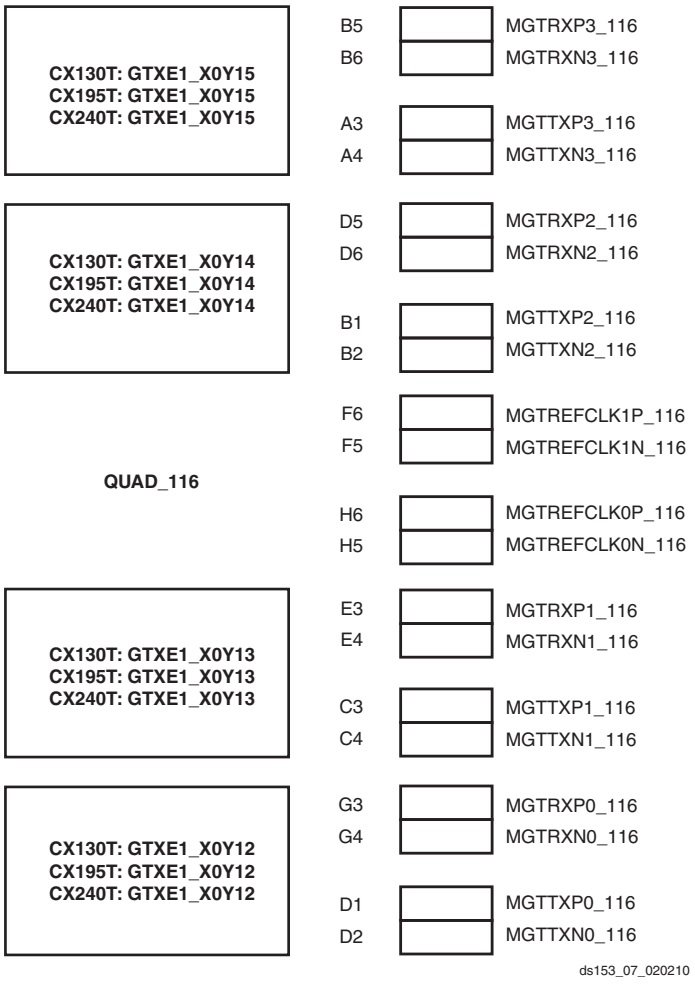

Figure 7: **Placement Diagram for the FF1156 Package (1 of 4)**

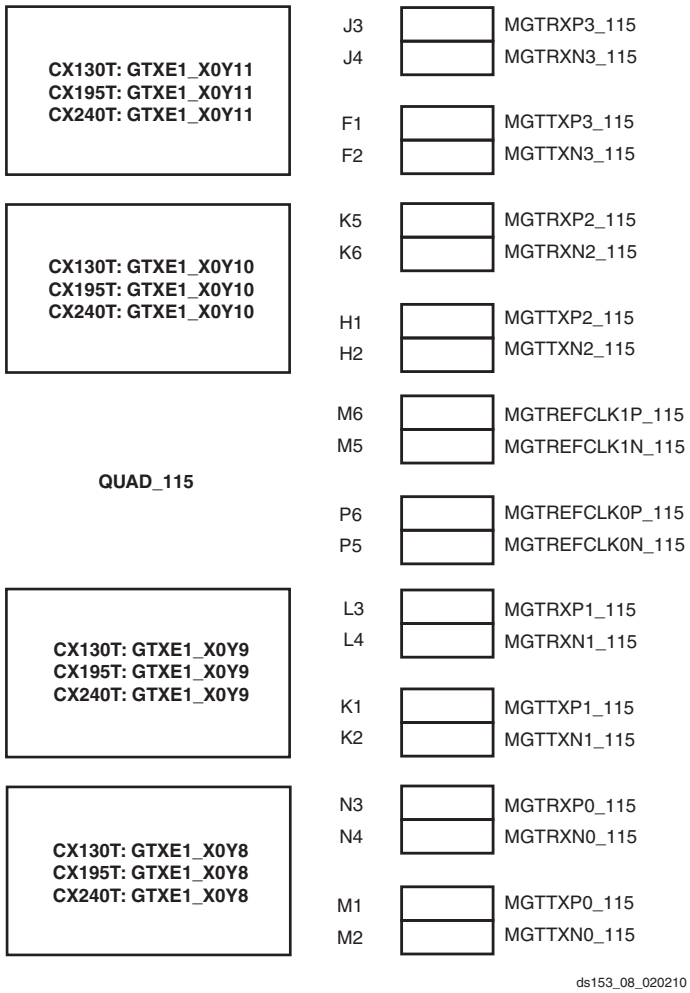

Figure 8: **Placement Diagram for the FF1156 Package (2 of 4)**

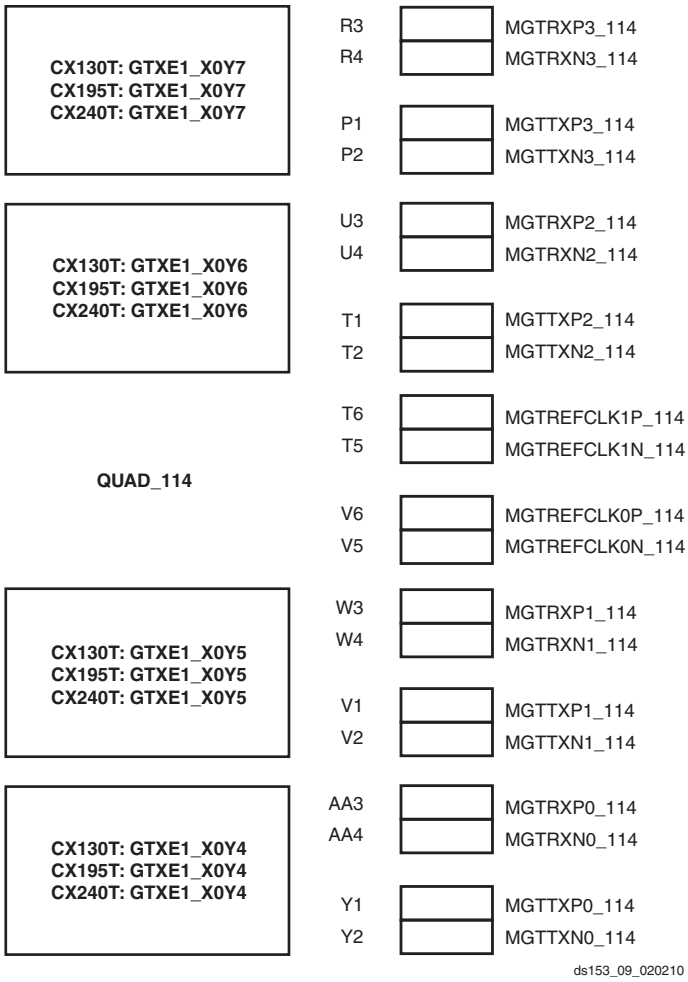

Figure 9: **Placement Diagram for the FF1156 Package (3 of 4)**

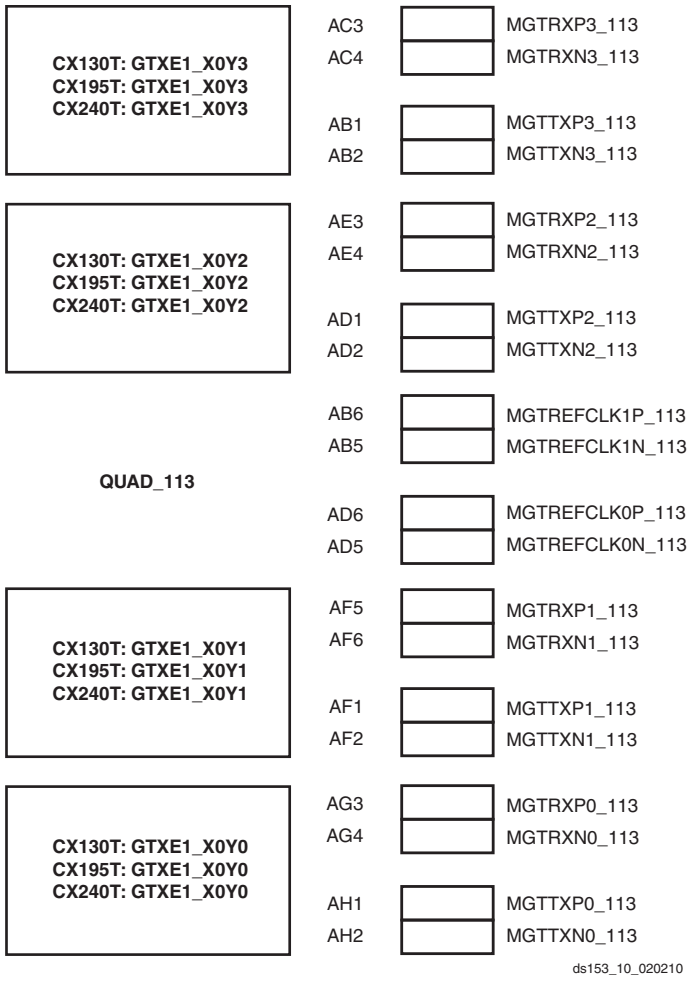

Figure 10: **Placement Diagram for the FF1156 Package (4 of 4)**

Table 10: **Recommended Operating Conditions**

Symbol	Description	Min	Max	Units
V_{CCINT}	Internal supply voltage relative to GND, T_j = 0°C to +85°C	0.95	1.05	V
	Internal supply voltage relative to GND, T_j = –40°C to +100°C	0.95	1.05	V
V_{CCAUX}	Auxiliary supply voltage relative to GND, T_j = 0°C to +85°C	2.375	2.625	V
	Auxiliary supply voltage relative to GND, T_j = –40°C to +100°C	2.375	2.625	V
V_{CCO}(1)(2)(3)	Supply voltage relative to GND, T_j = 0°C to +85°C	1.14	2.625	V
	Supply voltage relative to GND, T_j = –40°C to +100°C	1.14	2.625	V
V_{IN}	2.5V supply voltage relative to GND, T_j = 0°C to +85°C	GND – 0.20	2.625	V
	2.5V supply voltage relative to GND, T_j = –40°C to +100°C	GND – 0.20	2.625	V
	2.5V and below supply voltage relative to GND, T_j = 0°C to +85°C	GND – 0.20	V_{CCO} + 0.2	V
	2.5V and below supply voltage relative to GND, T_j = –40°C to +100°C	GND – 0.20	V_{CCO} + 0.2	V
I_{IN}(4)	Maximum current through any pin in a powered or unpowered bank when forward biasing the clamp diode.	–	10	mA
V_{BATT}(5)	Battery voltage relative to GND, T_j = 0°C to +85°C	1.0	2.5	V
	Battery voltage relative to GND, T_j = –40°C to +100°C	1.0	2.5	V
V_{FS}(6)	External voltage supply for eFUSE programming	2.375	2.625	V

Notes:

1. Configuration data is retained even if V_{CCO} drops to 0V.
2. Includes V_{CCO} of 1.2V, 1.5V, 1.8V, and 2.5V.
3. The configuration supply voltage V_{CC_CONFIG} is also known as V_{CCO_0}.
4. A total of 100 mA per bank should not be exceeded.
5. V_{BATT} is required only when using bitstream encryption. If battery is not used, connect V_{BATT} to either ground or V_{CCAUX}.
6. When not programming eFUSE, connect V_{FS} to GND.
7. All voltages are relative to ground.

Table 11: **DC Characteristics Over Recommended Operating Conditions(1)(2)**

Symbol	Description	Min	Typ	Max	Units
V_{DRINT}	Data retention V_{CCINT} voltage (below which configuration data might be lost)	0.75	–	–	V
V_{DRI}	Data retention V_{CCAUX} voltage (below which configuration data might be lost)	2.0	–	–	V
I_{REF}	V_{REF} leakage current per pin	–	–	10	µA
I_L	Input or output leakage current per pin (sample-tested)	–	–	10	µA
C_{IN}(3)	Die input capacitance at the pad	–	–	8	pF
I_{RPU}	Pad pull-up (when selected) @ V_{IN} = 0V, V_{CCO} = 2.5V	20	–	80	µA
	Pad pull-up (when selected) @ V_{IN} = 0V, V_{CCO} = 1.8V	8	–	40	µA
	Pad pull-up (when selected) @ V_{IN} = 0V, V_{CCO} = 1.5V	5	–	30	µA
	Pad pull-up (when selected) @ V_{IN} = 0V, V_{CCO} = 1.2V	1	–	20	µA
I_{RPD}	Pad pull-down (when selected) @ V_{IN} = 2.5V	3	–	80	µA
I_{BATT}	Battery supply current	–	–	150	nA
n	Temperature diode ideality factor	–	1.0002	–	n
r	Series resistance	–	5	–	Ω

Notes:

1. Typical values are specified at nominal voltage, 25°C.
2. Maximum value specified for worst case process at 25°C.
3. This measurement represents the die capacitance at the pad, not including the package.

LVPECL DC Specifications (LVPECL_25)

These values are valid when driving a 100Ω differential load only, i.e., a 100Ω resistor between the two receiver pins. The V_{OH} levels are 200 mV below standard LVPECL levels and are compatible with devices tolerant of lower common-mode ranges. Table 19 summarizes the DC output specifications of LVPECL. For more information on using LVPECL, see the *Virtex-6 FPGA SelectIO Resources User Guide*.

Table 19: **LVPECL DC Specifications**

Symbol	DC Parameter	Min	Typ	Max	Units
V_{OH}	Output High Voltage	V_{CC} – 1.025	1.545	V_{CC} – 0.88	V
V_{OL}	Output Low Voltage	V_{CC} – 1.81	0.795	V_{CC} – 1.62	V
V_{ICM}	Input Common-Mode Voltage	0.6	–	2.2	V
V_{IDIFF}	Differential Input Voltage(1)(2)	0.100	–	1.5	V

Notes:

1. Recommended input maximum voltage not to exceed V_{CCAUX} + 0.2V.
2. Recommended input minimum voltage not to go below –0.5V.

eFUSE Read Endurance

Table 20 lists the maximum number of read cycle operations expected. For more information, see the *Virtex-6 FPGA Configuration User Guide*.

Table 20: **eFUSE Read Endurance**

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
DNA_CYCLES	Number of DNA_PORT READ operations or JTAG ISC_DNA read command operations. Unaffected by SHIFT operations.	30,000,000				Read Cycles
AES_CYCLES	Number of JTAG FUSE_KEY or FUSE_CNTL read command operations. Unaffected by SHIFT operations.	30,000,000				Read Cycles

GTX Transceiver Specifications

GTX Transceiver DC Characteristics

Table 21: **Absolute Maximum Ratings for GTX Transceivers(1)**

Symbol	Description	Min	Max	Units
MGTAVCC	Analog supply voltage for the GTX transmitter and receiver circuits relative to GND	–0.5	1.1	V
MGTAVTT	Analog supply voltage for the GTX transmitter and receiver termination circuits relative to GND	–0.5	1.32	V
MGTAVTTRCAL	Analog supply voltage for the resistor calibration circuit of the GTX transceiver column	–0.5	1.32	V
V_{IN}	Receiver (RXP/RXN) and Transmitter (TXP/TXN) absolute input voltage	–0.5	1.32	V
$V_{MGTREFCLK}$	Reference clock absolute input voltage	–0.5	1.32	V

Notes:

1. Stresses beyond those listed under Absolute Maximum Ratings might cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time might affect device reliability.

Table 31: **GTX Transceiver Transmitter Switching Characteristics *(Cont'd)***

Symbol	Description	Condition	Min	Typ	Max	Units
T_{J480}	Total Jitter(2)(3)	480 Mb/s	–	–	0.1	UI
D_{J480}	Deterministic Jitter(2)(3)		–	–	0.03	UI

Notes:

1. Using same REFCLK input with TXENPMAPHASEALIGN enabled for up to four consecutive GTX transceiver sites.
2. Using PLL_DIVSEL_FB = 2, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
3. All jitter values are based on a bit-error ratio of $1e^{-12}$.
4. PLL frequency at 1.5625 GHz and OUTDIV = 1.
5. PLL frequency at 2.5 GHz and OUTDIV = 2.
6. PLL frequency at 2.5 GHz and OUTDIV = 4.

Table 32: **GTX Transceiver Receiver Switching Characteristics**

Symbol	Description		Min	Typ	Max	Units
F_{GTXRX}	Serial data rate	RX oversampler not enabled	0.600	–	F_{GTXMAX}	Gb/s
		RX oversampler enabled	0.480	–	0.600	Gb/s
$T_{RXELECIDLE}$	TIme for RXELECIDLE to respond to loss or restoration of data		–	75	–	ns
$R_{XOOBVDPP}$	OOB detect threshold peak-to-peak		60	–	150	mV
R_{XSST}	Receiver spread-spectrum tracking(1)	Modulated @ 33 KHz	–5000	–	0	ppm
R_{XRL}	Run length (CID)	Internal AC capacitor bypassed	–	–	512	UI
$R_{XPPMTOL}$	Data/REFCLK PPM offset tolerance	CDR 2nd-order loop disabled	–200	–	200	ppm
		CDR 2nd-order loop enabled	–2000	–	2000	ppm
SJ Jitter Tolerance(2)						
$JT\_SJ_{3.75}$	Sinusoidal Jitter(3)	3.75 Gb/s	0.44	–	–	UI
$JT\_SJ_{3.125}$	Sinusoidal Jitter(3)	3.125 Gb/s	0.45	–	–	UI
$JT\_SJ_{3.125L}$	Sinusoidal Jitter(3)	3.125 Gb/s(4)	0.45	–	–	UI
$JT\_SJ_{2.5}$	Sinusoidal Jitter(3)	2.5 Gb/s(5)	0.5	–	–	UI
$JT\_SJ_{1.25}$	Sinusoidal Jitter(3)	1.25 Gb/s(6)	0.5	–	–	UI
JT_SJ_{675}	Sinusoidal Jitter(3)	675 Mb/s	0.4	–	–	UI
JT_SJ_{480}	Sinusoidal Jitter(3)	480 Mb/s	0.4	–	–	UI
SJ Jitter Tolerance with Stressed Eye(2)						
$JT\_TJSE_{3.125}$	Total Jitter with Stressed Eye(7)	3.125 Gb/s	0.70	–	–	UI
$JT\_SJSE_{3.125}$	Sinusoidal Jitter with Stressed Eye(7)	3.125 Gb/s	0.1	–	–	UI

Notes:

1. Using PLL_RXDIVSEL_OUT = 1, 2, and 4.
2. All jitter values are based on a bit-error ratio of $1e^{-12}$.
3. The frequency of the injected sinusoidal jitter is 80 MHz.
4. PLL frequency at 1.5625 GHz and OUTDIV = 1.
5. PLL frequency at 2.5 GHz and OUTDIV = 2.
6. PLL frequency at 2.5 GHz and OUTDIV = 4.
7. Composite jitter with RX equalizer enabled. DFE disabled.

Performance Characteristics

This section provides the performance characteristics of some common functions and designs implemented in Virtex-6 CXT devices. The numbers reported here are worst-case values; they have all been fully characterized. These values are subject to the same guidelines as the Switching Characteristics, page 25.

Table 35: **Interface Performances**

Description	Speed Grade	
	-2	-1
Networking Applications		
SDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 8)	650 Mb/s	625 Mb/s
DDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 10)	1.25 Gb/s	1.0 Gb/s
SDR LVDS receiver (SFI-4.1)(1)	650 Mb/s	625 Mb/s
DDR LVDS receiver (SFI-4.2)(1)	1.0 Gb/s	0.9 Gb/s
Maximum Physical Interface (PHY) Rate for Memory Interfaces(2)(3)		
DDR2	666 Mb/s	666 Mb/s
DDR3	800 Mb/s	666 Mb/s
QDR II + SRAM	250 MHz	250 MHz

Notes:

1. LVDS receivers are typically bounded with certain applications where specific DPA algorithms dominate deterministic performance.
2. Based on Xilinx memory characterization platforms designed according to the guidelines in the *Virtex-6 FPGA Memory Interface Solutions User Guide*.
3. Consult the *Virtex-6 FPGA Memory Interface Solutions Data Sheet* for performance and feature information on memory interface cores (controller plus PHY).

Switching Characteristics

All values represented in this data sheet are based on the speed specification (version 1.08). Switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows:

Advance

These specifications are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

Preliminary

These specifications are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

Production

These specifications are released once enough production silicon of a particular device family member has been characterized to provide full correlation between specifications and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to Production before faster speed grades.

All specifications are always representative of worst-case supply voltage and junction temperature conditions.

Since individual family members are produced at different times, the migration from one category to another depends completely on the status of the fabrication process for each device.

Table 36 correlates the current status of each Virtex-6 CXT device on a per speed grade basis.

Table 36: **Virtex-6 CXT Device/Speed Grade Designations**

Device	Speed Grade Designations		
	Advance	Preliminary	Production
XC6VCX75T			-2, -1
XC6VCX130T			-2, -1
XC6VCX195T			-2, -1
XC6VCX240T			-2, -1

Testing of Switching Characteristics

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values.

For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer and back-annotate to the simulation net list. Unless otherwise noted, values apply to all Virtex-6 CXT devices.

Production Silicon and ISE Software Status

In some cases, a particular family member (and speed grade) is released to production before a speed specification is released with the correct label (Advance, Preliminary, Production). Any labeling discrepancies are corrected in subsequent speed specification releases. Table 37 lists the production released Virtex-6 family member, speed grade, and the minimum corresponding supported speed specification version and ISE software revisions. The ISE® software and speed specifications listed are the minimum releases required for production. All subsequent releases of software and speed specifications are valid.

Table 37: **Virtex-6 CXT Device/Production Software and Speed Specification Release**

Device	Speed Grade Designations	
	-2	-1
XC6VCX75T	ISE 12.2 (with speed file patch) v1.06	
XC6VCX130T	ISE 12.1 v1.04	
XC6VCX195T	ISE 12.2 (with speed file patch) v1.06	
XC6VCX240T	ISE 12.1 v1.04	

Notes:

1. Blank entries indicate a device and/or speed grade in advance or preliminary status.

Table 38: **IOB Switching Characteristics *(Cont'd)***

I/O Standard	T_{IOPI}		T_{IOOP}		T_{IOTP}		Units
	Speed Grade		Speed Grade		Speed Grade		
	-2	-1	-2	-1	-2	-1	
DIFF_SSTL18_II_T_DCI	1.09	1.09	1.67	1.67	1.67	1.67	ns
DIFF_SSTL15	1.06	1.06	1.71	1.71	1.71	1.71	ns
DIFF_SSTL15_DCI	1.06	1.06	1.68	1.68	1.68	1.68	ns
DIFF_SSTL15_T_DCI	1.06	1.06	1.68	1.68	1.68	1.68	ns

Table 39: **IOB 3-state ON Output Switching Characteristics (T_{IOTPHZ})**

Symbol	Description	Speed Grade		Units
		-2	-1	
T_{IOTPHZ}	T input to Pad high-impedance	0.99	0.99	ns

I/O Standard Adjustment Measurement Methodology

Input Delay Measurements

Table 40 shows the test setup parameters used for measuring input delay.

Table 40: **Input Delay Measurement Methodology**

Description	I/O Standard Attribute	V_L (1)(2)	V_H (1)(2)	V_{MEAS} (1,4,5)	V_{REF} (1,3,5)
LVCMOS, 2.5V	LVCMOS25	0	2.5	1.25	–
LVCMOS, 1.8V	LVCMOS18	0	1.8	0.9	–
LVCMOS, 1.5V	LVCMOS15	0	1.5	0.75	–
HSTL (High-Speed Transceiver Logic), Class I & II	HSTL_I, HSTL_II	V_{REF} – 0.5	V_{REF} + 0.5	V_{REF}	0.75
HSTL, Class III	HSTL_III	V_{REF} – 0.5	V_{REF} + 0.5	V_{REF}	0.90
HSTL, Class I & II, 1.8V	HSTL_I_18, HSTL_II_18	V_{REF} – 0.5	V_{REF} + 0.5	V_{REF}	0.90
HSTL, Class III 1.8V	HSTL_III_18	V_{REF} – 0.5	V_{REF} + 0.5	V_{REF}	1.08
SSTL (Stub Terminated Transceiver Logic), Class I & II, 3.3V	SSTL3_I, SSTL3_II	V_{REF} – 1.00	V_{REF} + 1.00	V_{REF}	1.5
SSTL, Class I & II, 2.5V	SSTL2_I, SSTL2_II	V_{REF} – 0.75	V_{REF} + 0.75	V_{REF}	1.25
SSTL, Class I & II, 1.8V	SSTL18_I, SSTL18_II	V_{REF} – 0.5	V_{REF} + 0.5	V_{REF}	0.90
LVDS (Low-Voltage Differential Signaling), 2.5V	LVDS_25	1.2 – 0.125	1.2 + 0.125	0(6)	–
LVDSEXT (LVDS Extended Mode), 2.5V	LVDSEXT_25	1.2 – 0.125	1.2 + 0.125	0(6)	–
HT (HyperTransport), 2.5V	LDT_25	0.6 – 0.125	0.6 + 0.125	0(6)	–

Notes:

1. The input delay measurement methodology parameters for LVDCI are the same for LVCMOS standards of the same voltage. Input delay measurement methodology parameters for HSLVDCI are the same as for HSTL_II standards of the same voltage. Parameters for all other DCI standards are the same for the corresponding non-DCI standards.
2. Input waveform switches between V_L and V_H.
3. Measurements are made at typical, minimum, and maximum V_{REF} values. Reported delays reflect worst case of these measurements. V_{REF} values listed are typical.
4. Input voltage level from which measurement starts.
5. This is an input voltage reference that bears no relation to the V_{REF} / V_{MEAS} parameters found in IBIS models and/or noted in Figure 14.
6. The value given is the differential output voltage.

Table 41: **Output Delay Measurement Methodology *(Cont'd)***

Description	I/O Standard Attribute	R_{REF} (Ω)	C_{REF}[1] (pF)	V_{MEAS} (V)	V_{REF} (V)
HT (HyperTransport), 2.5V	LDT_25	100	0	0[2]	0.6
LVPECL (Low-Voltage Positive Emitter-Coupled Logic), 2.5V	LVPECL_25	100	0	0[2]	0
LVDCI/HSLVDCI, 2.5V	LVDCI_25, HSLVDCI_25	1M	0	1.25	0
LVDCI/HSLVDCI, 1.8V	LVDCI_18, HSLVDCI_18	1M	0	0.9	0
LVDCI/HSLVDCI, 1.5V	LVDCI_15, HSLVDCI_15	1M	0	0.75	0
HSTL (High-Speed Transceiver Logic), Class I & II, with DCI	HSTL_I_DCI, HSTL_II_DCI	50	0	V_{REF}	0.75
HSTL, Class III, with DCI	HSTL_III_DCI	50	0	0.9	1.5
HSTL, Class I & II, 1.8V, with DCI	HSTL_I_DCI_18, HSTL_II_DCI_18	50	0	V_{REF}	0.9
HSTL, Class III, 1.8V, with DCI	HSTL_III_DCI_18	50	0	1.1	1.8
SSTL (Stub Series Termi.Logic), Class I & II, 1.8V, with DCI	SSTL18_I_DCI, SSTL18_II_DCI	50	0	V_{REF}	0.9
SSTL, Class I & II, 2.5V, with DCI	SSTL2_I_DCI, SSTL2_II_DCI	50	0	V_{REF}	1.25

Notes:

1. C_{REF} is the capacitance of the probe, nominally 0 pF.
2. The value given is the differential output voltage.

Input/Output Logic Switching Characteristics

Table 42: **ILOGIC Switching Characteristics**

Symbol	Description	Speed Grade		Units
		-2	-1	
Setup/Hold				
T_{ICE1CK}/T_{ICKCE1}	CE1 pin Setup/Hold with respect to CLK	0.27/0.04	0.27/0.04	ns
T_{ISRCK}/T_{ICKSR}	SR pin Setup/Hold with respect to CLK	0.96/–0.10	0.96/–0.10	ns
T_{IDOCK}/T_{IOCKD}	D pin Setup/Hold with respect to CLK without Delay	0.10/0.54	0.10/0.54	ns
T_{IDOCKD}/T_{IOCKDD}	DDLY pin Setup/Hold with respect to CLK (using IODELAY)	0.14/0.42	0.14/0.40	ns
Combinatorial				
T_{IDI}	D pin to O pin propagation delay, no Delay	0.20	0.20	ns
T_{IDID}	DDLY pin to O pin propagation delay (using IODELAY)	0.25	0.25	ns
Sequential Delays				
T_{IDLO}	D pin to Q1 pin using flip-flop as a latch without Delay	0.64	0.64	ns
T_{IDLOD}	DDLY pin to Q1 pin using flip-flop as a latch (using IODELAY)	0.68	0.68	ns
T_{ICKQ}	CLK to Q outputs	0.71	0.71	ns
T_{RQ_ILOGIC}	SR pin to OQ/TQ out	1.15	1.15	ns
T_{GSRQ_ILOGIC}	Global Set/Reset to Q outputs	10.51	10.51	ns
Set/Reset				
T_{RPW_ILOGIC}	Minimum Pulse Width, SR inputs	1.20	1.20	ns, Min

Table 43: **OLOGIC Switching Characteristics**

Symbol	Description	Speed Grade		Units
		-2	-1	
Setup/Hold				
T_{ODCK}/T_{OCKD}	D1/D2 pins Setup/Hold with respect to CLK	0.54/–0.11	0.54/–0.11	ns
T_{OOCECK}/T_{OCKOCE}	OCE pin Setup/Hold with respect to CLK	0.22/–0.05	0.22/–0.05	ns
T_{OSRCK}/T_{OCKSR}	SR pin Setup/Hold with respect to CLK	0.71/–0.29	0.71/–0.29	ns
T_{OTCK}/T_{OCKT}	T1/T2 pins Setup/Hold with respect to CLK	0.56/–0.10	0.56/–0.10	ns
T_{OTCECK}/T_{OCKTCE}	TCE pin Setup/Hold with respect to CLK	0.21/–0.05	0.21/–0.05	ns
Combinatorial				
T_{DOQ}	D1 to OQ out or T1 to TQ out	1.01	1.01	ns
Sequential Delays				
T_{OCKQ}	CLK to OQ/TQ out	0.71	0.71	ns
T_{RQ}	SR pin to OQ/TQ out	1.05	1.05	ns
T_{GSRQ}	Global Set/Reset to Q outputs	10.51	10.51	ns
Set/Reset				
T_{RPW}	Minimum Pulse Width, SR inputs	1.20	1.20	ns, Min

Input Serializer/Deserializer Switching Characteristics

Table 44: **ISERDES Switching Characteristics**

Symbol	Description	Speed Grade		Units
		-2	-1	
Setup/Hold for Control Lines				
$T_{ISCCK\_BITSLIP}/T_{ISCKC\_BITSLIP}$	BITSLIP pin Setup/Hold with respect to CLKDIV	0.09/0.17	0.09/0.17	ns
$T_{ISCCK\_CE}/T_{ISCKC\_CE}$ (2)	CE pin Setup/Hold with respect to CLK (for CE1)	0.27/0.04	0.27/0.04	ns
$T_{ISCCK\_CE2}/T_{ISCKC\_CE2}$ (2)	CE pin Setup/Hold with respect to CLKDIV (for CE2)	–0.06/0.31	–0.06/0.31	ns
Setup/Hold for Data Lines				
T_{ISDCK_D}/T_{ISCKD_D}	D pin Setup/Hold with respect to CLK	0.09/0.11	0.09/0.11	ns
$T_{ISDCK\_DDLY}/T_{ISCKD\_DDLY}$	DDLY pin Setup/Hold with respect to CLK (using IODELAY) (1)	0.14/0.07	0.14/0.07	ns
$T_{ISDCK\_D\_DDR}/T_{ISCKD\_D\_DDR}$	D pin Setup/Hold with respect to CLK at DDR mode	0.09/0.11	0.09/0.11	ns
$T_{ISDCK\_DDLY\_DDR}$ $T_{ISCKD\_DDLY\_DDR}$	D pin Setup/Hold with respect to CLK at DDR mode (using IODELAY) (1)	0.14/0.07	0.14/0.07	ns
Sequential Delays				
T_{ISCKO_Q}	CLKDIV to out at Q pin	0.75	0.75	ns
Propagation Delays				
T_{ISDO_DO}	D input to DO output pin	0.25	0.25	ns

Notes:

1. Recorded at 0 tap value.
2. T_{ISCCK_CE2} and T_{ISCKC_CE2} are reported as $T_{ISCCK\_CE}/T_{ISCKC\_CE}$ in a TRACE report.

Input/Output Delay Switching Characteristics

Table 46: **Input/Output Delay Switching Characteristics**

Symbol	Description	Speed Grade		Units
		-2	-1	
IDELAYCTRL				
T_{DLYCCO_RDY}	Reset to Ready for IDELAYCTRL	3	3	µs
$F_{IDELAYCTRL\_REF}$	REFCLK frequency	200	200	MHz
IDELAYCTRL_REF_PRECISION	REFCLK precision	±10	±10	MHz
$T_{IDELAYCTRL\_RPW}$	Minimum Reset pulse width	50	50	ns
IODELAY				
$T_{IDELAYRESOLUTION}$	IODELAY Chain Delay Resolution	1/(32 x 2 x F_{REF})		ps
$T_{IDELAYPAT\_JIT}$	Pattern dependent period jitter in delay chain for clock pattern.(1)	0	0	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern.(2)	±5	±5	ps per tap
	Pattern dependent period jitter in delay chain for random data pattern.(3)	±9	±9	ps per tap
$T_{IODELAY\_CLK\_MAX}$	Maximum frequency of CLK input to IODELAY	300	300	MHz
T_{IODCCK_CE} / T_{IODCKC_CE}	CE pin Setup/Hold with respect to CK	0.65/–0.09	0.65/–0.09	ns
T_{IODCK_INC}/ T_{IODCKC_INC}	INC pin Setup/Hold with respect to CK	0.31/–0.00	0.31/–0.00	ns
T_{IODCCK_RST}/ T_{IODCKC_RST}	RST pin Setup/Hold with respect to CK	0.69/–0.08	0.69/–0.08	ns
T_{IODDO_T}	TSCONTROL delay to MUXE/MUXF switching and through IODELAY	Note 4	Note 4	ps
$T_{IODDO\_IDATAIN}$	Propagation delay through IODELAY	Note 4	Note 4	ps
$T_{IODDO\_ODATAIN}$	Propagation delay through IODELAY	Note 4	Note 4	ps

Notes:

1. When HIGH_PERFORMANCE mode is set to TRUE or FALSE.
2. When HIGH_PERFORMANCE mode is set to TRUE
3. When HIGH_PERFORMANCE mode is set to FALSE.
4. Delay depends on IODELAY tap setting. See the TRACE report for actual values.

CLB Switching Characteristics

Table 47: **CLB Switching Characteristics**

Symbol	Description	Speed Grade		Units
		-2	-1	
Combinatorial Delays				
T_{ILO}	An – Dn LUT address to A	0.08	0.08	ns, Max
	An – Dn LUT address to AMUX/CMUX	0.23	0.25	ns, Max
	An – Dn LUT address to BMUX_A	0.37	0.41	ns, Max
T_{ITO}	An – Dn inputs to A – D Q outputs	0.79	0.91	ns, Max
T_{AXA}	AX inputs to AMUX output	0.42	0.48	ns, Max
T_{AXB}	AX inputs to BMUX output	0.47	0.53	ns, Max
T_{AXC}	AX inputs to CMUX output	0.52	0.60	ns, Max
T_{AXD}	AX inputs to DMUX output	0.55	0.63	ns, Max

Table 47: **CLB Switching Characteristics *(Cont'd)***

Symbol	Description	Speed Grade		Units
		-2	-1	
T_{BXB}	BX inputs to BMUX output	0.39	0.45	ns, Max
T_{BXD}	BX inputs to DMUX output	0.50	0.58	ns, Max
T_{CXB}	CX inputs to CMUX output	0.34	0.38	ns, Max
T_{CXD}	CX inputs to DMUX output	0.40	0.45	ns, Max
T_{DXD}	DX inputs to DMUX output	0.38	0.44	ns, Max
T_{OPCYA}	An input to COUT output	0.42	0.47	ns, Max
T_{OPCYB}	Bn input to COUT output	0.42	0.47	ns, Max
T_{OPCYC}	Cn input to COUT output	0.35	0.39	ns, Max
T_{OPCYD}	Dn input to COUT output	0.33	0.37	ns, Max
T_{AXCY}	AX input to COUT output	0.33	0.38	ns, Max
T_{BXCY}	BX input to COUT output	0.28	0.32	ns, Max
T_{CXCY}	CX input to COUT output	0.20	0.23	ns, Max
T_{DXCY}	DX input to COUT output	0.19	0.22	ns, Max
T_{BYP}	CIN input to COUT output	0.08	0.09	ns, Max
T_{CINA}	CIN input to AMUX output	0.28	0.32	ns, Max
T_{CINB}	CIN input to BMUX output	0.29	0.34	ns, Max
T_{CINC}	CIN input to CMUX output	0.30	0.34	ns, Max
T_{CIND}	CIN input to DMUX output	0.33	0.38	ns, Max
Sequential Delays				
T_{CKO}	Clock to AQ – DQ outputs	0.39	0.44	ns, Max
T_{SHCKO}	Clock to AMUX – DMUX outputs	0.47	0.54	ns, Max
Setup and Hold Times of CLB Flip-Flops Before/After Clock CLK				
T_{DICK}/T_{CKDI}	A – D input to CLK on A – D Flip Flops	0.43/0.20	0.50/0.23	ns, Min
$T_{CECK\_CLB}/T_{CKCE\_CLB}$	CE input to CLK on A – D Flip Flops	0.32/–0.01	0.37/–0.01	ns, Min
T_{SRCK}/T_{CKSR}	SR input to CLK on A – D Flip Flops	0.52/–0.08	0.60/–0.08	ns, Min
T_{CINCK}/T_{CKCIN}	CIN input to CLK on A – D Flip Flops	0.24/0.17	0.27/0.19	ns, Min
Set/Reset				
T_{SRMIN}	SR input minimum pulse width	0.97	0.97	ns, Min
T_{RQ}	Delay from SR input to AQ – DQ flip-flops	0.68	0.78	ns, Max
T_{CEO}	Delay from CE input to AQ – DQ flip-flops	0.59	0.67	ns, Max
F_{TOG}	Toggle frequency (for export control)	1098.00	1098.00	MHz

Notes:

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.
2. These items are of interest for Carry Chain applications.

Block RAM and FIFO Switching Characteristics

Table 50: **Block RAM and FIFO Switching Characteristics**

Symbol	Description	Speed Grade		Units
		-2	-1	
Block RAM and FIFO Clock-to-Out Delays				
T_{RCKO_DO} and $T_{RCKO\_DO\_REG}$[1]	Clock CLK to DOUT output (without output register)[2][3]	2.08	2.39	ns, Max
	Clock CLK to DOUT output (with output register)[4][5]	0.75	0.86	ns, Max
$T_{RCKO\_DO\_ECC}$ and $T_{RCKO\_DO\_ECC\_REG}$	Clock CLK to DOUT output with ECC (without output register)[2][3]	3.30	3.79	ns, Max
	Clock CLK to DOUT output with ECC (with output register)[4][5]	0.86	0.98	ns, Max
T_{RCKO_CASC} and $T_{RCKO\_CASC\_REG}$	Clock CLK to DOUT output with Cascade (without output register)[2]	3.18	3.65	ns, Max
	Clock CLK to DOUT output with Cascade (with output register)[4]	1.58	1.81	ns, Max
T_{RCKO_FLAGS}	Clock CLK to FIFO flags outputs[6]	0.91	1.05	ns, Max
$T_{RCKO\_POINTERS}$	Clock CLK to FIFO pointers outputs[7]	1.09	1.25	ns, Max
$T_{RCKO\_RDCOUNT}$	Clock CLK to FIFO Read Counter	1.09	1.25	ns, Max
$T_{RCKO\_WRCOUNT}$	Clock CLK to FIFO Write Counter	1.09	1.25	ns, Max
$T_{RCKO\_SDBIT\_ECC}$ and $T_{RCKO\_SDBIT\_ECC\_REG}$	Clock CLK to BITERR (with output register)	0.76	0.87	ns, Max
	Clock CLK to BITERR (without output register)	2.84	3.26	ns, Max
$T_{RCKO\_PARITY\_ECC}$	Clock CLK to ECCPARITY in ECC encode only mode	1.06	1.21	ns, Max
$T_{RCKO\_RDADDR\_ECC}$ and $T_{RCKO\_RDADDR\_ECC\_REG}$	Clock CLK to RDADDR output with ECC (without output register)	0.90	1.03	ns, Max
	Clock CLK to RDADDR output with ECC (with output register)	0.92	1.06	ns, Max
Setup and Hold Times Before/After Clock CLK				
$T_{RCCK\_ADDR}/T_{RCKC\_ADDR}$	ADDR inputs[8]	0.62/0.32	0.72/0.37	ns, Min
T_{RDCK_DI}/T_{RCKD_DI}	DIN inputs[9]	1.11/0.34	1.28/0.39	ns, Min
$T_{RDCK\_DI\_ECC}/T_{RCKD\_DI\_ECC}$	DIN inputs with block RAM ECC in standard mode[9]	0.59/0.34	0.68/0.39	ns, Min
	DIN inputs with block RAM ECC encode only[9]	0.85/0.34	0.97/0.39	ns, Min
	DIN inputs with FIFO ECC in standard mode[9]	1.02/0.34	1.17/0.39	ns, Min
$T_{RCCK\_CLK}/T_{RCKC\_CLK}$	Inject single/double bit error in ECC mode	1.20/0.29	1.38/0.33	ns, Min
$T_{RCCK\_RDEN}/T_{RCKC\_RDEN}$	Block RAM Enable (EN) input	0.41/0.30	0.47/0.34	ns, Min
$T_{RCCK\_REGCE}/T_{RCKC\_REGCE}$	CE input of output register	0.22/0.31	0.25/0.35	ns, Min
$T_{RCCK\_RSTREG}/T_{RCKC\_RSTREG}$	Synchronous RSTREG input	0.28/0.26	0.32/0.29	ns, Min
$T_{RCCK\_RSTRAM}/T_{RCKC\_RSTRAM}$	Synchronous RSTRAM input	0.41/0.27	0.47/0.31	ns, Min
T_{RCCK_WE}/T_{RCKC_WE}	Write Enable (WE) input (block RAM only)	0.52/0.35	0.60/0.40	ns, Min
$T_{RCCK\_WREN}/T_{RCKC\_WREN}$	WREN FIFO inputs	0.55/0.30	0.64/0.34	ns, Min
$T_{RCCK\_RDEN}/T_{RCKC\_RDEN}$	RDEN FIFO inputs	0.55/0.30	0.63/0.34	ns, Min
Reset Delays				
T_{RCO_FLAGS}	Reset RST to FIFO Flags/Pointers[10]	1.10	1.27	ns, Max
$T_{RCCK\_RSTREG}/T_{RCKC\_RSTREG}$	FIFO reset timing[11]	0.28/0.26	0.32/0.29	ns, Min

Table 50: **Block RAM and FIFO Switching Characteristics *(Cont'd)***

Symbol	Description	Speed Grade		Units
		-2	-1	
Maximum Frequency				
F_{MAX}	Block RAM (Write First and No Change modes)	400	350	MHz
	Block RAM (Read First mode)	400	347	MHz
	Block RAM (SDP mode)(12)	400	347	MHz
$F_{MAX\_CASCADE}$	Block RAM Cascade (Write First and No Change modes)	400	347	MHz
	Block RAM Cascade (Read First mode)	350	304	MHz
F_{MAX_FIFO}	FIFO in all modes	400	350	MHz
F_{MAX_ECC}	Block RAM and FIFO in ECC configuration	325	282	MHz

Notes:

1. TRACE will report all of these parameters as T_{RCKO_DO}.
2. T_{RCKO_DOR} includes T_{RCKO_DOW}, T_{RCKO_DOPR}, and T_{RCKO_DOPW} as well as the B port equivalent timing parameters.
3. These parameters also apply to synchronous FIFO with DO_REG = 0.
4. T_{RCKO_DO} includes T_{RCKO_DOP} as well as the B port equivalent timing parameters.
5. These parameters also apply to multirate (asynchronous) and synchronous FIFO with DO_REG = 1.
6. T_{RCKO_FLAGS} includes the following parameters: T_{RCKO_AEMPTY}, T_{RCKO_AFULL}, T_{RCKO_EMPTY}, T_{RCKO_FULL}, T_{RCKO_RDERR}, T_{RCKO_WRERR}.
7. $T_{RCKO\_POINTERS}$ includes both $T_{RCKO\_RDCOUNT}$ and $T_{RCKO\_WRCOUNT}$.
8. The ADDR setup and hold must be met when EN is asserted (even when WE is deasserted). Otherwise, block RAM data corruption is possible.
9. T_{RCKO_DI} includes both A and B inputs as well as the parity inputs of A and B.
10. T_{RCO_FLAGS} includes the following flags: AEMPTY, AFULL, EMPTY, FULL, RDERR, WRERR, RDCOUNT, and WRCOUNT.
11. The FIFO reset must be asserted for at least three positive clock edges.
12. When using ISE software v12.4 or later, if the RDARRDR_COLLISION_HWCONFIG attribute is set to PERFORMANCE or the block RAM is in single-port operation, then the faster F_{MAX} for WRITE_FIRST/NO_CHANGE modes apply.

Table 51: **DSP48E1 Switching Characteristics *(Cont'd)***

Symbol	Description	Speed Grade		Units
		-2	-1	
Clock to Outs from Input Register Clock to Cascading Output Pins				
$T_{DSPCKO\_\{ACOUT;\ BCOUT\}\_\{AREG;\ BREG\}}$	CLK (AREG, BREG) to {P, CARRYOUT} output	0.89	1.02	ns
$T_{DSPCKO\_\{PCOUT,\ CARRYCASCOUT,\ MULTSIGNOUT\}\_\{AREG,\ BREG\}\_MULT}$	CLK (AREG, BREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output using multiplier	5.49	6.31	ns
$T_{DSPCKO\_\{PCOUT,\ CARRYCASCOUT,\ MULTSIGNOUT\}\_\{AREG,\ BREG\}}$	CLK (AREG, BREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output not using multiplier	2.40	2.76	ns
$T_{DSPCKO\_\{PCOUT,\ CARRYCASCOUT,\ MULTSIGNOUT\}\_DREG\_MULT}$	CLK (DREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output using multiplier	5.38	6.18	ns
$T_{DSPCKO\_\{PCOUT,\ CARRYCASCOUT,\ MULTSIGNOUT\}\_CREG}$	CLK (CREG) to {PCOUT, CARRYCASCOUT, MULTSIGNOUT} output	2.40	2.76	ns
Maximum Frequency				
F_{MAX}	With all registers used	350	275	MHz
F_{MAX_PATDET}	With pattern detector	350	275	MHz
$F_{MAX\_MULT\_NOMREG}$	Two register multiply without MREG	262	227	MHz
$F_{MAX\_MULT\_NOMREG\_PATDET}$	Two register multiply without MREG with pattern detect	241	209	MHz
$F_{MAX\_PREADD\_MULT\_NOADREG}$	Without ADREG	292	253	MHz
$F_{MAX\_PREADD\_MULT\_NOADREG\_PATDET}$	Without ADREG with pattern detect	292	253	MHz
$F_{MAX\_NOPIPELINEREG}$	Without pipeline registers (MREG, ADREG)	196	170	MHz
$F_{MAX\_NOPIPELINEREG\_PATDET}$	Without pipeline registers (MREG, ADREG) with pattern detect	184	160	MHz

Table 52: **Configuration Switching Characteristics *(Cont'd)***

Symbol	Description	Speed Grade		Units
		-2	-1	
BPI Master Flash Mode Programming Switching				
T_{BPICCO}(2)	ADDR[25:0], RS[1:0], FCS_B, FOE_B, FWE_B outputs valid after CCLK rising edge at 2.5V	6	6	ns
	ADDR[25:0], RS[1:0], FCS_B, FOE_B, FWE_B outputs valid after CCLK rising edge at 1.8V	6	6	ns
T_{BPIDCC}/T_{BPICCD}	Setup/Hold on D[15:0] data input pins	4.0/0.0	4.0/0.0	ns
$T_{INITADDR}$	Minimum period of initial ADDR[25:0] address cycles	3	3	CCLK cycles
SPI Master Flash Mode Programming Switching				
$T_{SPIDCC}/T_{SPIDCCD}$	DIN Setup/Hold before/after the rising CCLK edge	3.0/0.0	3.0/0.0	ns
T_{SPICCM}	MOSI clock to out at 2.5V	6	6	ns
	MOSI clock to out at 1.8V	6	6	ns
$T_{SPICCFC}$	FCS_B clock to out at 2.5V	6	6	ns
	FCS_B clock to out at 1.8V	6	6	ns
$T_{FSINIT}/T_{FSINITH}$	FS[2:0] to INIT_B rising edge Setup and Hold	2	2	µs
CCLK Output (Master Modes)				
T_{MCCKL}	Master CCLK clock Low time duty cycle	45/55	45/55	%, Min/Max
T_{MCCKH}	Master CCLK clock High time duty cycle	45/55	45/55	%, Min/Max
CCLK Input (Slave Modes)				
T_{SCCKL}	Slave CCLK clock minimum Low time	2.5	2.5	ns, Min
T_{SCCKH}	Slave CCLK clock minimum High time	2.5	2.5	ns, Min
Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK				
F_{DCK}	Maximum frequency for DCLK	200	200	MHz
$T_{MMCMDCK\_DADDR}/T_{MMCMCKD\_DADDR}$	DADDR Setup/Hold	1.63/0.00	1.63/0.00	ns
$T_{MMCMDCK\_DI}/T_{MMCMCKD\_DI}$	DI Setup/Hold	1.63/0.00	1.63/0.00	ns
$T_{MMCMDCK\_DEN}/T_{MMCMCKD\_DEN}$	DEN Setup/Hold time	1.63/0.00	1.63/0.00	ns
$T_{MMCMDCK\_DWE}/T_{MMCMCKD\_DWE}$	DWE Setup/Hold time	1.63/0.00	1.63/0.00	ns
$T_{MMCMCKO\_DO}$	CLK to out of DO(3)	3.64	3.64	ns
$T_{MMCMCKO\_DRDY}$	CLK to out of DRDY	0.38	0.38	ns

Notes:

1. To support longer delays in configuration, use the design solutions described in *Virtex-6 FPGA Configuration Guide*.
2. Only during configuration, the last edge is determined by a weak pull-up/pull-down resistor in the I/O.
3. DO will hold until next DRP operation.

Clock Buffers and Networks

Table 53: **Global Clock Switching Characteristics (Including BUFGCTRL)**

Symbol	Description	Speed Grade		Units
		-2	-1	
$T_{BCCCK\_CE}/T_{BCCKC\_CE}$(1)	CE pins Setup/Hold	0.16/0.00	0.16/0.00	ns
T_{BCCCK_S}/T_{BCCKC_S}(1)	S pins Setup/Hold	0.16/0.00	0.16/0.00	ns
T_{BCCKO_O}(2)	BUFGCTRL delay from I0/I1 to O	0.10	0.10	ns
Maximum Frequency				
F_{MAX}	Global clock tree (BUFG)	700	700	MHz

Notes:

1. T_{BCCCK_CE} and T_{BCCKC_CE} must be satisfied to assure glitch-free operation of the global clock when switching between clocks. These parameters do not apply to the BUFGMUX_VIRTEX4 primitive that assures glitch-free operation. The other global clock setup and hold times are optional; only needing to be satisfied if device operation requires simulation matches on a cycle-for-cycle basis when switching between clocks.
2. T_{BGCKO_O} (BUFG delay from I0 to O) values are the same as T_{BCCKO_O} values.

Table 54: **Input/Output Clock Switching Characteristics (BUFIO)**

Symbol	Description	Speed Grade		Units
		-2	-1	
T_{BIOCKO_O}	Clock to out delay from I to O	0.18	0.18	ns
Maximum Frequency				
F_{MAX}	I/O clock tree (BUFIO)	710	710	MHz

Date	Version	Description of Revisions
06/08/10	1.2	Revised GTX Transceivers in CXT Devices, page 5. Added V_{FS} and revised the V_{IN} and V_{TS} values in Table 9, page 11. Added V_{FS} and note 6 to Table 10. Revised description of C_{IN} in Table 11, including adding note 3. Updated Table 13 including adding note 2. Removed DIFF SSTL15 and added values to SSTL15 in Table 15. Updated Table 16 through Table 19. Added eFUSE Read Endurance section. Updated entire GTX Transceivers in CXT Devices section. Changed specifications of PCI Express in Table 34. In Table 35, removed RLDRAM II and revised and added values to other interface performance specifications. Updated speed specification to v1.04 with appropriate changes to Table 36. Revised the IOB switching characteristics in Table 38. Updated values in Table 39 and note 4 in Table 41. ILOGIC (Table 42), OLOGIC (Table 43), ISERDES (Table 44), and OSERDES (Table 45) switching characteristics changes. Revised $T_{IODELAY\_CLK\_MAX}$ and $T_{IDELAYPAT\_JIT}$ in Table 46. Revised CLB switching characteristics and added T_{SHCKO} to Table 47and revised CLB switching characteristics in Table 48 and Table 49. In Table 50, removed $T_{RCKO\_RDCOUNT}$ and $T_{RCKO\_WRCOUNT}$, removed $T_{RCKO\_PARITY\_ECC}$: Clock CLK to ECCPARITY in standard ECC mode, revised $T_{RDCK\_DI\_ECC}$/$T_{RCKD\_DI\_ECC}$, $T_{RCKO\_POINTERS}$, and revised F_{MAX} and $F_{MAX\_CASCADE}$ switching characteristics. Multiple changes to configuration specifications in Table 52. Revised switching characteristics and global clock tree (BUFG) F_{MAX} in Table 53. Revised switching characteristics and I/O clock tree (BUFIO) F_{MAX} in Table 54. Added note 1 to Table 55. Revised the F_{MAX} horizontal clock tree (BUFH) in Table 56. Multiple changes to MMCM specifications in Table 57 including F_{INMAX} and F_{OUTMAX}. Updated switching characteristics in Table 58 through Table 63. Removed T_{DCD_BUFH} and $T_{BUFHSKEW}$ from Table 64.
06/30/10	1.3	Production release of XC6VCX130T and XC6VCX240T in Table 36 and Table 37. Updated -1 speed grade SDR values in Table 35. Updated BUFIO F_{MAX} specification in Table 54. Added Note 6 to Table 57.
07/28/10	1.4	Production release of XC6VCX75T and XC6VCX195T in Table 36 and Table 37 using ISE 12.2 software with speed file v1.06 using the *Speed File Patch*. Updated PCI compliance on page 1. Added values to Table 13. In Table 25, update $V_{CMOUTDC}$ equation to MGTAVTT – DV_{PPOUT}/4. Updated F_{MAX} in Table 53, Table 54, and Table 56. Updated F_{INMAX} and F_{OUTMAX} in Table 57. Updated values in Table 61, Table 62, and Table 63.
10/14/10	1.5	Moved data sheet to Production status on the first page. Updated speed file with ISE 12.3 software with speed file v1.08 using the *Speed File Patch.* In Table 51, updated values for $T_{DSPCKO\_\{PCOUT,}$ CARRYCASCOUT, MULTSIGNOUT}_PREG.
02/11/11	1.6	Updated Table 10 to include the industrial range specifications. Added Note 12 to Table 50. Revised T_{BPICCO} values in Table 52. Updated range description for F_{INDUTY} in Table 57 and added note 8. The following revisions are due to specification changes as described in XCN11009, *Virtex-6 FPGA: Data Sheet, User Guides, and JTAG ID Updates*. In Table 52, updated the values for T_{SMCCKW}, T_{SPIDCC}, T_{SPICCM}, and $T_{SPICCFC}$. In Table 57: MMCM Specification, added bandwidth settings to F_{PFDMIN} and added note 1.